



The EICROC Project

Update on EICROC0 testing effort at IJCLab and perspectives eRD112/ AC-LGAD meeting, 06/06/2023

Dominique Marchand on behalf of the EICROC Project Team

<u>Ultimate objective</u>: **Development** and **characterization** of an **ASIC EICROC (32 x 32)** able to read-out the new generation of pixelated (500 x 500 μm²) silicon sensors: **AC-LGAD** (Low-Gain Avalanche Diode) coupled **AC** for the **Electron Ion Collider** (EIC) Far Forward detectors: the **Roman Pots**



OUTLINE

Present objective: ASIC prototype (EICROC0 : 16 channels, 4 x 4) design and characterization dedicated to the read-out of AC-LGAD pixelated silicon sensors (500 x 500 μm²) for the EIC Roman Pots

- **EICROCO** Requirements
- EICROC0 Design
- EICROC test bench @ IJCLab (Orsay, France)
- Progress report on EICROC0 characterization
 - Charge injection system
 - **TZ Pre Amplifier Probe output signals: amplitude versus injected charge**
 - **TDC Performance**
 - **DADC Performance**
- Summary
- Perspectives
- EICROC Project status



(timing & position)







Compared to ALTIROC, ToT TDC (non-linear behavior versus the deposited charge) replaced by an ADC (8 bits)

EICROCO: EIC Roman Pots 4x4 AC-LGAD readout test chip



- Submitted through a Multi Project Wafer (130 nm CMOS technology) in March 22 EICROC0 chips delivered mid-July 22
- > Test board (PCB) designed by OMEGA, 10 pieces delivered end of July 22
 - test board partially cabled by IJCLab
- Wire-bonding of EICROC0 to test boards by BNL collaborators
- Delivery at IJCLab of 3 test boards w/ EICROC0 chip in Oct. 22
- Interface board (Xilinx ZC 706): (I²C communication)firmware/software developments (IJCLab)





Status of EICROC0 Test Bench at UCLab



- ¹²C communication (firmware dev.)
- Data stream written/read
- EICROC0 DC levels
- Discri. threshold exploration
- **EICROC0** charge injection system fixed
- **<u>EICROC0 decoding</u>** (TDC, ADC) Firmware + software updated

External trigger: signal directly injected into TDC (No input into Pre Amplifier nor discriminator)

EICROC0 test bench operational since March '23

Preliminary studies [board #2 w/ EICROC0, no AC-LGAD]

- Characterization of the charge injection system
- Pre Amplifier output signal amplitudes vs injected charge
- ➢ Noise evaluation & evaluation of couplings to 160 MHz clock
- TDC performance
- ADC performance



In configuration file: Global parameter: Register **0x20C** dacb_pulser [**0** (Max value) -> **63** (Min value)]



man



EICROC0 TZ Pre Amplifier Probe output signals

Pixel / Channel Mapping	Column 0	Column 1	Column 2	Column 3
Line 0	Pixel (0 ,0)	Pixel (1 ,0)	Pixel (2 ,0)	Pixel (3 ,0)
	#00	#04	#08	#12
Line 1	Pixel (0 ,1)	Pixel (1 ,1)	Pixel (2 ,1)	Pixel (3 ,1)
	#01	#05	#09	#13
Line 2	Pixel (0 ,2)	Pixel (1, 2)	Pixel (2 ,2)	Pixel (3 ,2)
	#02	#06	#10	#14
Line 3	Pixel (0,3)	Pixel (1,3)	Pixel (2 ,3)	Pixel (3 ,3)
	#03	#07	#11	#15





PA output signals through SMA connector s (PCB back plane)

< P# > : Probe PA associated to **column**#

Feature of EICROCO: Observing 4 Probe PA channels <u>simultaneously</u>

1 Probe PA per column *Ex.: #00, #04, #08, #12*



Look at preamplifier probe output (one probe PA per column). Input charge 12.5 fC (CMD pulse 125 mV)



EICROC0 TZ Pre Amplifier Probe output signal amplitudes (5)



|Probe PA Max. Ampl.| vs channel number for several dacb_pulser value



EICROC0 TZ Pre Amplifier Probe output signal amplitudes (2)



"Amplitude" refers as |peak amplitude|



< |Max. Amplitude | > 95.5 mV, RMS 1.36 mV

(Channel #8)



EICROC0 TZ Pre Amplifier Probe output signal amplitudes (3)

PA |Max. Amplitude | vs channel number



PA Probe output not designed to be uniform:

- Max. Amplitude | decreases along one column
- Variation from column to column (possible attenuation from column to column could currently come from the use of different cable length for each column)

Rise (Fall) Time (RT) computed between 10% and 90% of |Max. - Ampl.|

Rise Time (RT) vs channel number



Variation of RT value from column to column

- Slight variation within one column
- Probe output signal is probably slightly slower than PA signal processed by TDC, due to the Probe Follower

EICROC0 TZ Pre Amplifier Probe output signal amplitudes (6)

Output Probe PA Jitter Evaluation

On scope, data (Time ; Amplitude) recorded event by event (pulse corresponding to each trigger) Time distribution computed for a Constant Fraction discriminator (*threshold at 20 % of the |Max. Ampl.*]) With a linear extrapolation between samples $\sigma = 0.37 [100 \text{ ps unit}] \rightarrow \text{Jitter} = 37 \text{ ps}$

Jitter **quite good BUT** theoretical jitter would be: 0.9 ns (rise time) / [95,5 (signal) / 1.3 (noise)] = **12 ps**

Injected Q [fC]	Jitter [ps]
25.00	34
12.50	37
6.25	41

Need to investigate floor jitter contribution from command pulse injection



12.5 fC input charge

Probe PA Jitter [ps] vs injected charge [fC]





Preamplifier performance with clock switched ON/OFF

160 MHz clock (mandatory for TDC) [40MHz inherited from 160 MHz (/4) for ADC]



When **160 MHz** clock is **ON**: noise **larger by a factor 5-6** due to a clear **coupling** to the PA input

Sill under investigation (ground PA, PCB...) but up to now limitation for Time measurement with TDC





* Nominal TDC quantification step: 25 ps

Slope region 1 (2) : 24,6 (24,2) ps => in fair agreement with nominal TDC quantification step

Can be adjusted to nominal through slow control parameters



EICROC0 TDC Characterization (2)

TDC distribution for pixel 0





Time correlation

between2 channels

Clock noise strongly correlated between channels → computation of time difference

> $\Delta T = 0.79 \text{ TDC units}$ $\rightarrow 19.7 \text{ ps}$

Assuming an identical resolution for each channel:

The achievable TDC time resolution is:

19.7/sqrt(2) = **14 ps**

for the entire chain (PA+discri+TDC) if PA clock coupling issue is solved

[DACB_pulserused: 250 mV]

Individual TOA jitter not so good



PA is followed by an integrator digitized with a 8 bits 40 MHz ADC providing 8 time samples (every 25 ns)





EICROCO ADC (8 bits) Characterization (2)





- EICROCO test bench operational at IJCLab
- So far only 1 board w/ EICROC0 « alone » under test
- > Individually Pre Amplifier, TDC and ADC performances are in agreement with design
- > 4 simultaneous PA Probe outputs can be efficiently exploited for detector characterization
- > Observed integration/noise/coupling issues require further investigation:
 - 160 MHz clock coupling to PA
 - low frequency noise ADC (integrator?)



- Keep on investigating board w/ « ASIC alone » (noise & coupling, more systematics measurements, crosstalk) [IJCLab –OMEGA]
- > Testing board #4 (w/ EICROCO and AC-LGAD sensor) => evaluation of charge sharing [IJCLab]
- Start EICROCO characterization at BNL (basic documentation sent), support from IJCLab and OMEGA
- > Development of software scripts to automate acquisition and analysis software tools [BNL-IJCLab]
- Production of additional (or new) EICROCO PCB, depending on results of coupling/noise investigations (more EICROCO chips will be available within 3 to 4 months)
- Start design of next ASIC iteration (fixing observed issues, ..., lower power consumption ADC?, EIC clocks?)



CNTS IN2P3 officially supports <u>MEGA</u> Technical Contribution in EIC ASIC designs

Funding

- Université Paris-Saclay (P2IO): 75 k€ [2021 2022]
- DOE/eRD109: 75 k€ (contract not signed yet due to delay on the French CNRS side
- => will be spent for EICROC next ASIC iteration: EICROC0_v1
 - (Submission foreseen 1st quarter of 2024)

- DOE/eRD109 « FY2024 » proposal: plan to request 90 k€ budget for EICROC1 submission

Human Resources reinforcement

- OMEGA:

- ➤ + Adrien Verplancke (engineer) involved in EIC ASIC design and characterization [May '23 on]
- +1 PhD student starting Fall '23
- IJCLab:
 - ➤ +1 intern student (2nd year Egineering schoolBoudjerouna [May July 2023]
 - > Université Paris-Saclay (P2I): 60 k€ grant obtained (June '23) to hire a postdoc for **1 year**



- Sofiane Boudjerouna (intern)
- Beng Yun Ky
- Dominique Marchand
- Carlos Munoz Camacho



- Laurent Serin
- Ana-Sofia Torrento
- Pu-Kaï Wang (PhD, last year)



- Florent Bouyjou - Eric Delagnes
- Pierrick DinaucourtNathalie Seguin-Moreau
- Christophe de la Taille
- Maxime Morenas
- Adrien Verplancke



Alessandro Tricoli's team

The EICROC0 Project: a team effort

Thank you





Back-Up



EICROC0 characterization: Probe PA Amplitude 25 fC input charge



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EICROC0 characterization: Probe PA Amplitude 14.1 fC input charge



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EICROC0 characterization: Probe PA Amplitude 6 fC input charge



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EICROC0 TZ Pre Amplifier Probe output signal amplitudes (4)

Probe PA Max. Ampl. vs channel number for several dacb_pulser value



Oscilloscope: 50 Ω termination for each Probe PA channel

06/06/2023

EICROC0 TZ Pre Amplifier Probe output signal amplitudes (5)





In configuration file: Global Parameter **10bitDAC** [**0** (Min. value) -> **1023** (Max. value)] Registers **0x20A** [7:0] & **0x20B** [xxxxx]-[**9:8**] Most significant bits **J5 connector (DC level)**



06/06/2023



EICROC0: 1 pad (500 x 500 µm²)

overview



- ➢ High speed TZ PA and discriminator (from ALTIROC)
- ➢ I²C slow control (from CMS HGCROC)
- 8 bits 40 MHz ADC (adapted from HGCROC 10 bits ADC, M. Idzik et al., AGH Krakow)
- Digital readout FIFO (depth 8, 200 ns)
- > 10 bits **TDC** (TOA) designed by **CEA Irfu/DEDIP**:

HGCROC TDC (1 mm x 120 μ m):

- spatially adapted to fit in a pixel of 0.5 x 0.5 \mbox{mm}^2
- optimization in terms of dynamic range and resolution
 - (10 ps rms) as well as power consumption
- common block for calibration of all TDC channels

★ 5 slow control bytes/pixel:

- 6 bits local threshold
- 6 bits ADC pedestal
- 16 TDC calibration bits
- Various on/off and probes



EICROC0 layout (1 pad = 1 channel)



EICROCO boards repartition status (June 1st, 2023)							
Board	Location	EICROC0	AC- LGAD	Modifications/comment	Status		
B1	Nantes?	✓	X	None For HGTD 40 MHz PLL testing (OMEGA)	Presently activated		
B2	IJCLab	\checkmark	X	R5 & R17 (cmd_pulser) replaced (90Ω -> 150Ω) + Jumper alim + Jumper (spare 1 - spare 2)	Under test		
B3	OMEGA	\checkmark	x	None For HGTD 40 MHz PLL testing	Retrieved from irradiation		
B4	OMEGA *	~	~	R5 & R17 (cmd_pulser) replaced (90Ω -> 150Ω)R57&R58 values inversed: replacedR54&R52 values inversed: replacedReg. M13 & M14 cabled upside down: replaced	Under investigation		
B#	OMEGA *	X	X	None	Part. cabled		
B#	OMEGA *	x	X	None	Part. cabled		
B#	BNL	\checkmark		Reg. M13, M14 OK (photo)			
B#	BNL	X		Reg. M13, M14 OK (photo)			
B#	BNL	X		Reg. M13, M14 OK (photo)			
B10	Irfu/DEDIP	X	X	None	Part. cabled		

* Board transferred from BNL to CERN (Christophe) in Feb 2023.

EICROCO chips left: 7 at BNL, 6 at CEA/Irfu [20 currently considered lost ...]

Xilinx ZC706 boards: 1 at IJCLab, 1 presently isolated in Nantes (OMEGA), 1 at Irfu, 1 (or 2) at BNL?